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**Aehr Test Systems to Present at the Craig-Hallum Alpha Select Conference
in New York on November 16, 2016**

Fremont, CA (November 4, 2016) - Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that Gayn Erickson, President and CEO, and Ken Spink, CFO, will present at the Craig-Hallum Seventh Annual Alpha Select Conference on Wednesday, November 16, 2016 at 3:30 p.m. Eastern Time. The conference is being held at the Sheraton New York Times Square Hotel in New York City.

To arrange a one-on-one meeting with Aehr Test management, please contact either your Craig-Hallum sales person, or the MKR Group, Aehr Test's investor relations firm, at aehr@mkr-group.com.

A live audio webcast will be available on the Investor Relations section of Aehr Test's website at www.aehr.com. A replay of the webcast will be made available for 90 days following the event.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems and WaferPak contactors. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. For more information, please visit Aehr Test's website at www.aehr.com.

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